CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

Integra Technologies Inc.
3718 N. Rock Road, Suite 800
Wichita, KS 67226

Fulfills the requirements of

ISO/IEC 17025:2017

and the

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 19 August 2026

Certificate Number: AT-3120

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

Integra Technologies Inc.

3718 N Rock Road Suite 800
Wichita, KS 67226
John Montgomery John.Montgomery@integra-tech.com
316 630 6874

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to the **Integra Technologies Inc.** to perform the following AS6171 slash sheet tests:

TESTING

ISO/IEC 17025 Accreditation Granted: **19 August 2024**

Certificate Number: **AT-3120** Certificate Expiry Date: **19 August 2026**

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
External Visual Inspection	AS6171/2 Method A & B AS6081 Sect 4.2.6.4.2 IDEA-STD-1010	Electrical, Electronic and Electromechanical (EEE) Components	Keyence & Meiji scopes w/camera or equivalent
Scanning Electron Microscopy (SEM) Examination / Inspection	AS6171/2 Method F AS6081 Sect 4.2.6.4.3 C		JOEL SEM or equivalent
Physical Dimensions	AS6171/2 Method E AS6081 Sect 4.2.6.4.2.2		Keyence scopes or equivalent & calipers
Resistance to Solvents	AS6171/2 Method C & D A6081 Sect 4.2.6.4.3 A & B		Solvents
Contact plating composition and thickness	AS6171/3 AS6081 Sect 4.2.6.4.5		Oxford Instruments, X-Strata 980 JOEL SEM or equivalent
Delid/Decapsulation Physical Analysis	AS6171/4 AS6081 Sect 4.2.6.4.6		FALIT laser ablation or equivalent Chemical Lab – acids Mechanical delid tools

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Radiological (X-ray) Inspection	AS6171/5 AS6081 Sect 4.2.6.4.4 MIL-STD-883/750/202	Electrical, Electronic and Electromechanical (EEE) Components	Nikon XTV-160 real time X-Ray or equivalent
Acoustic Microscopy	AS6171/6 AS6081 Appendix C.6 MIL-STD-883, Method 2030 J-STD-020, J-STD-035		Okos VUE 400-P or equivalent

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test: Resistors, Capacitors, Inductors, Relays, connectors, Microcircuits and Semiconductor devices	AS6171/7 Table 2, AS6081 Appendix C.3	Electronic Components	Multiple A.T.E. Equipment Sets
Burn-In	AS6171/7 AS6081 Appendix C.4	Electrical, Electronic and Electromechanical (EEE) Components	AEHR Oven or equivalent

Jason Stine, Vice President

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